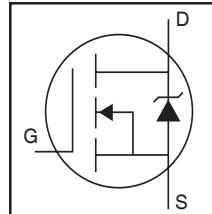


# IRFR4615PbF

# IRFU4615PbF

## Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

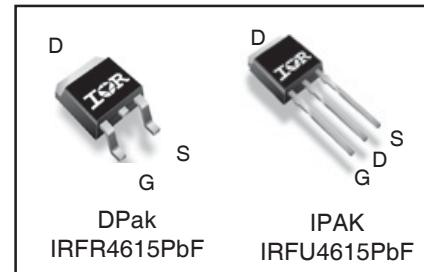


HEXFET® Power MOSFET

<b>V<sub>DSS</sub></b>	<b>150V</b>
<b>R<sub>DS(on)</sub></b>	<b>typ.</b> <b>34mΩ</b>
	<b>max.</b> <b>42mΩ</b>
<b>I<sub>D</sub></b>	<b>33A</b>

## Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free



G	D	S
Gate	Drain	Source

## Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	33	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	24	
I <sub>DM</sub>	Pulsed Drain Current ①	140	W
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Maximum Power Dissipation	144	
	Linear Derating Factor	0.96	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery ③	38	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 175	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

## Avalanche Characteristics

E <sub>AS</sub> (Thermally limited)	Single Pulse Avalanche Energy ②	109	mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig. 14, 15, 22a, 22b,	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①		mJ

## Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case ⑧	—	1.045	°C/W
R <sub>θJA</sub>	Junction-to-Ambient (PCB Mount) ⑦	—	50	
R <sub>θJA</sub>	Junction-to-Ambient	—	110	

## ORDERING INFORMATION:

See detailed ordering and shipping information on the last page of this data sheet.

Notes ① through ⑧ are on page 11

[www.irf.com](http://www.irf.com)

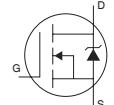
**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

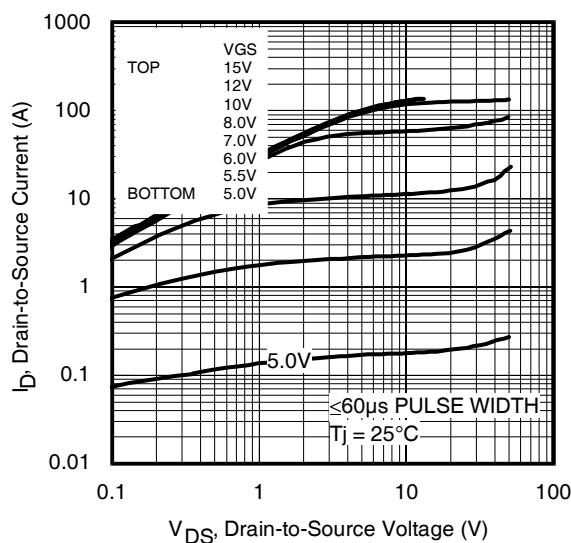
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	150	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.19	—	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 5\text{mA}$ ①
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	34	42	$\text{m}\Omega$	$V_{GS} = 10\text{V}, I_D = 21\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	20	$\mu\text{A}$	$V_{DS} = 150\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 150\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20\text{V}$
$R_{G(\text{int})}$	Internal Gate Resistance	—	2.7	—	$\Omega$	

**Dynamic @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

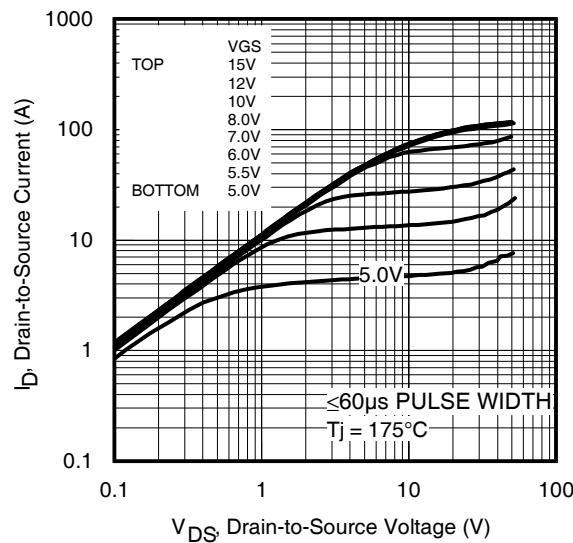
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	35	—	—	S	$V_{DS} = 50\text{V}, I_D = 21\text{A}$
$Q_g$	Total Gate Charge	—	26	—	nC	$I_D = 21\text{A}$
$Q_{gs}$	Gate-to-Source Charge	—	8.6	—		$V_{DS} = 75\text{V}$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	9.0	—		$V_{GS} = 10\text{V}$ ④
$Q_{\text{sync}}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )	—	17	—		$I_D = 21\text{A}, V_{DS} = 0\text{V}, V_{GS} = 10\text{V}$
$t_{d(on)}$	Turn-On Delay Time	—	15	—	ns	$V_{DD} = 98\text{V}$
$t_r$	Rise Time	—	35	—		$I_D = 21\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	25	—		$R_G = 7.3\Omega$
$t_f$	Fall Time	—	20	—		$V_{GS} = 10\text{V}$ ④
$C_{iss}$	Input Capacitance	—	1750	—	pF	$V_{GS} = 0\text{V}$
$C_{oss}$	Output Capacitance	—	155	—		$V_{DS} = 50\text{V}$
$C_{rss}$	Reverse Transfer Capacitance	—	40	—		$f = 1.0\text{MHz}$ (See Fig.5)
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related) ⑥	—	179	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V}$ to $120\text{V}$ ⑥(See Fig.11)
$C_{oss \text{ eff. (TR)}}$	Effective Output Capacitance (Time Related) ⑤	—	382	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V}$ to $120\text{V}$ ⑤

**Diode Characteristics**

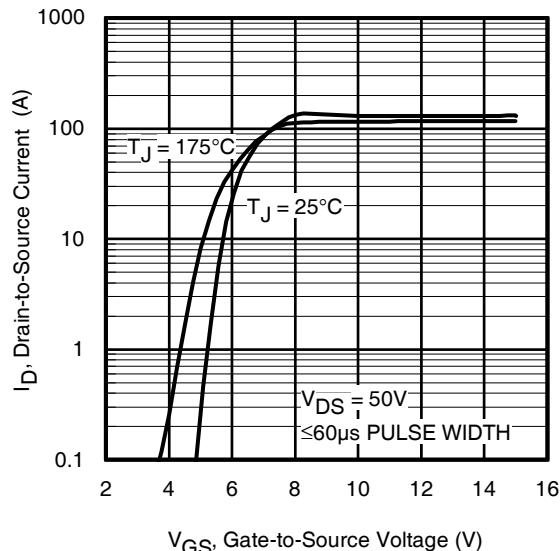
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	33	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	140		
$V_{SD}$	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_s = 21\text{A}, V_{GS} = 0\text{V}$ ④
$t_{rr}$	Reverse Recovery Time	—	70	—	ns	$T_J = 25^\circ\text{C}$ $V_R = 100\text{V}$ ,
		—	83	—		$T_J = 125^\circ\text{C}$ $I_F = 21\text{A}$
$Q_{rr}$	Reverse Recovery Charge	—	177	—	nC	$T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}$ ④
		—	247	—		$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current	—	4.9	—	A	$T_J = 25^\circ\text{C}$
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				



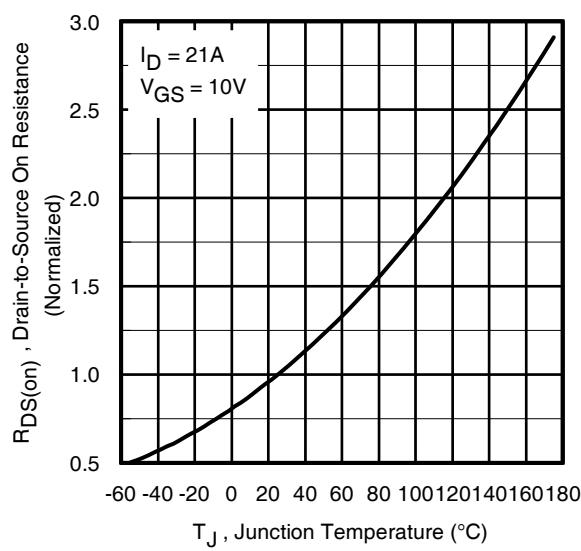
**Fig 1.** Typical Output Characteristics



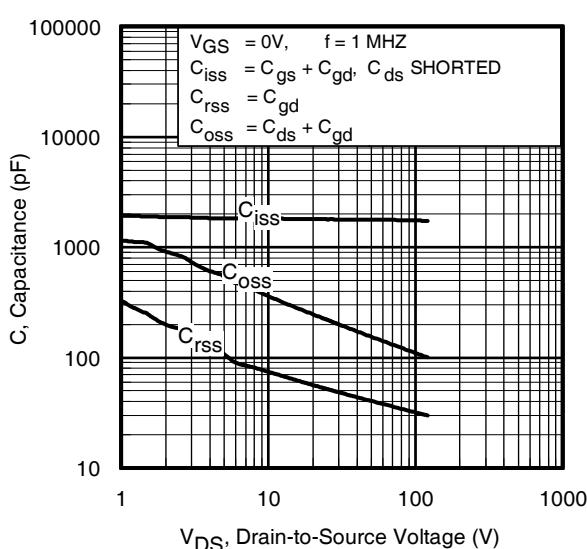
**Fig 2.** Typical Output Characteristics



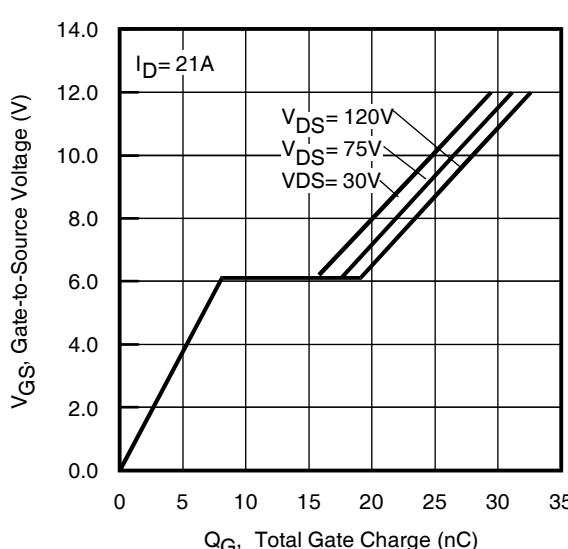
**Fig 3.** Typical Transfer Characteristics



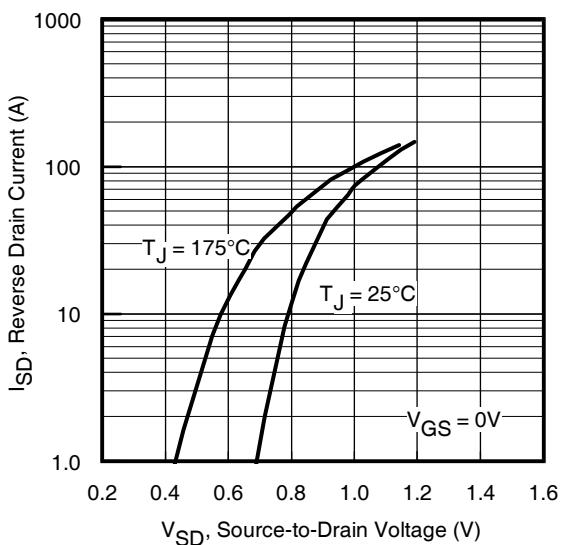
**Fig 4.** Normalized On-Resistance vs. Temperature



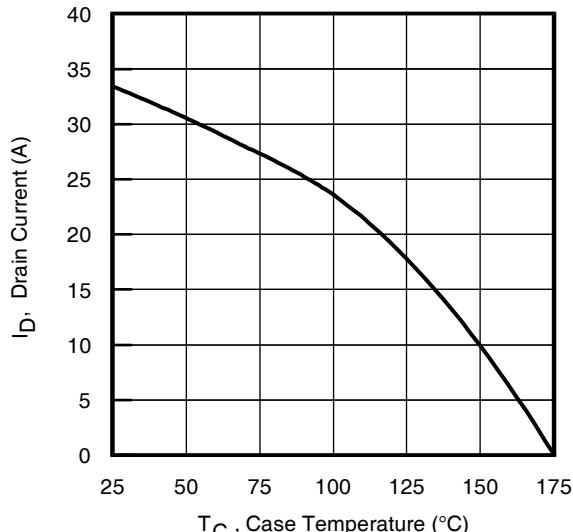
**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



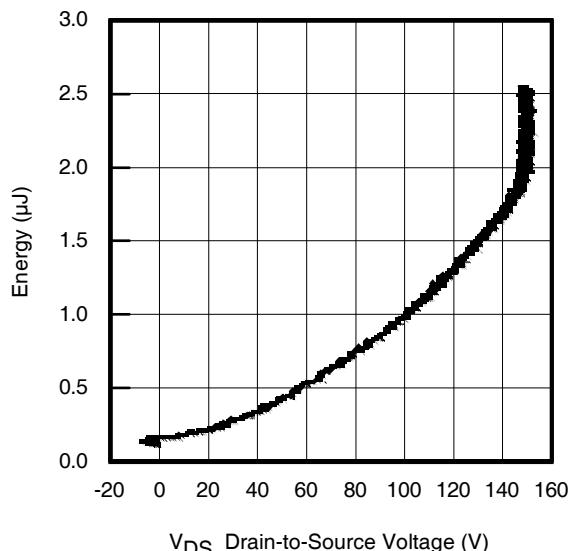
**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage



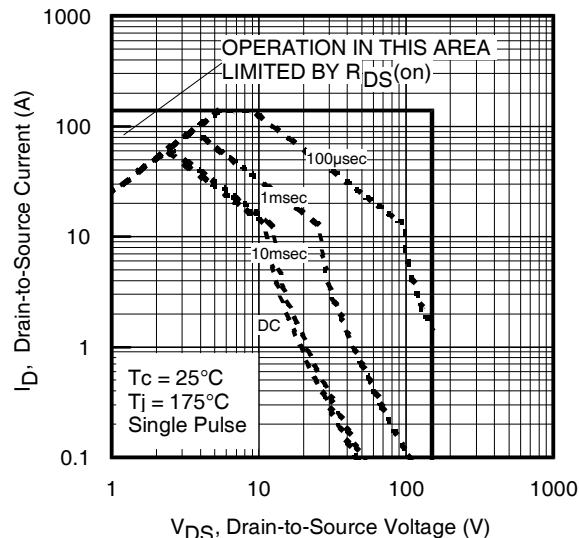
**Fig 7.** Typical Source-Drain Diode Forward Voltage



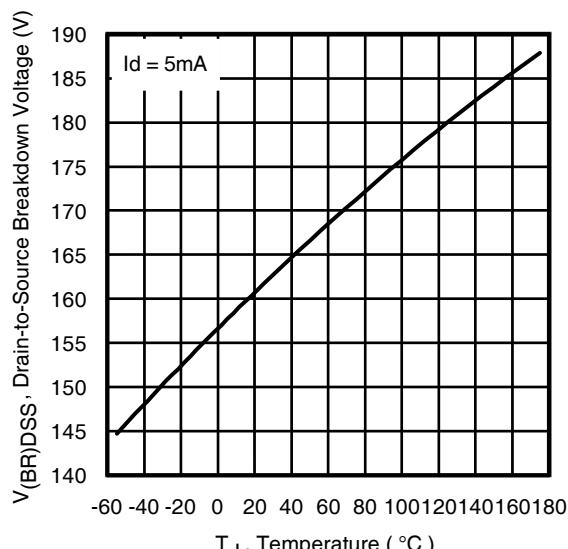
**Fig 9.** Maximum Drain Current vs. Case Temperature



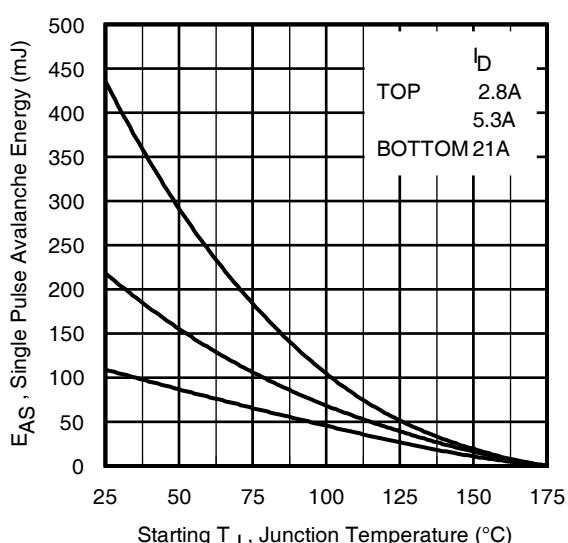
**Fig 11.** Typical  $C_{oss}$  Stored Energy



**Fig 8.** Maximum Safe Operating Area



**Fig 10.** Drain-to-Source Breakdown Voltage



**Fig 12.** Maximum Avalanche Energy vs. Drain Current

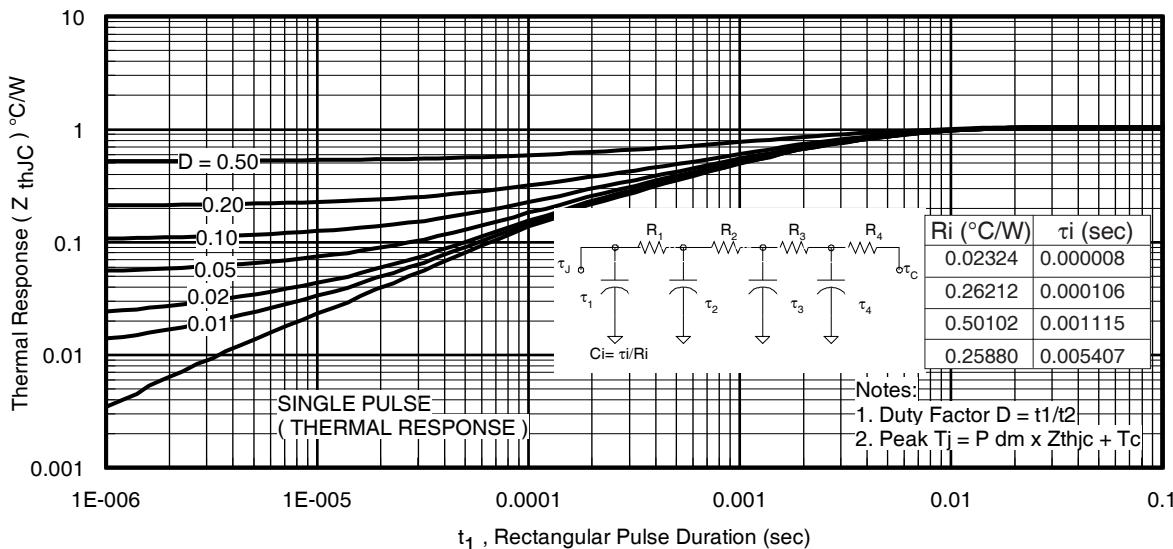


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

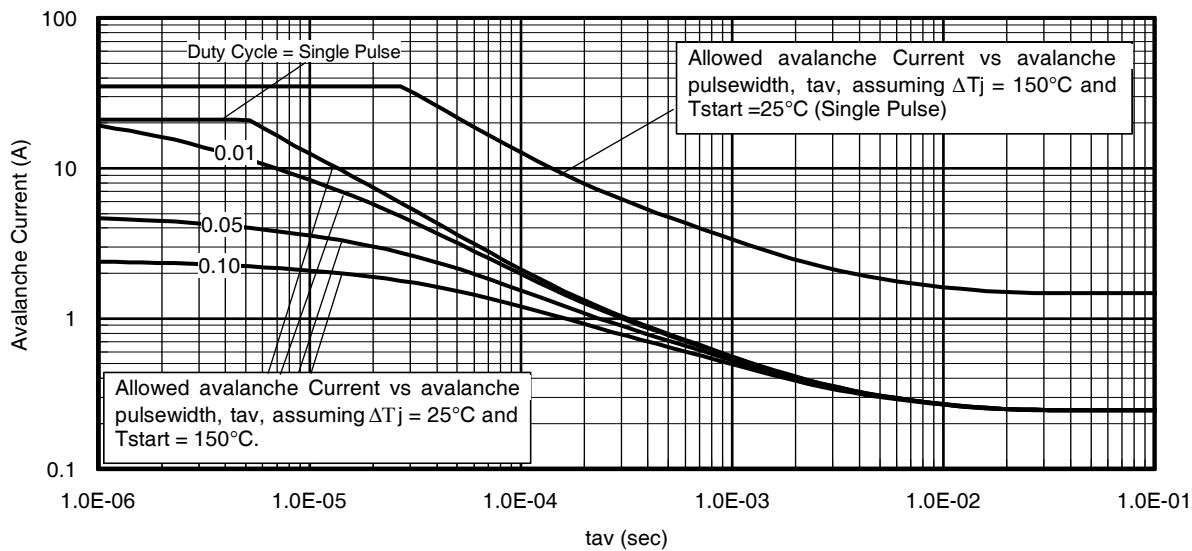
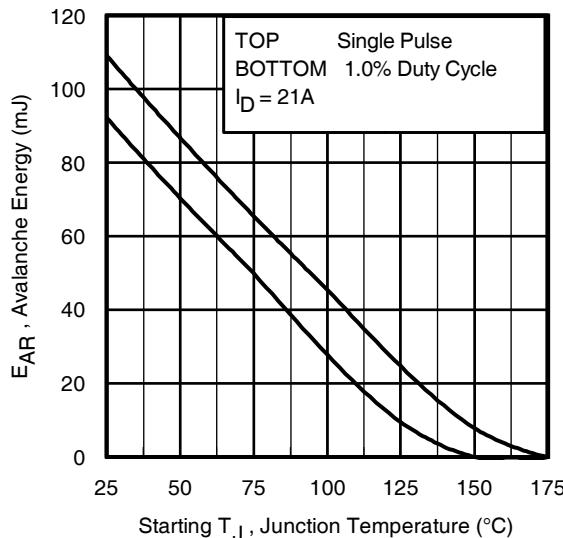


Fig 14. Typical Avalanche Current vs.Pulsewidth



Notes on Repetitive Avalanche Curves , Figures 14, 15:  
 (For further info, see AN-1005 at [www.irf.com](http://www.irf.com))

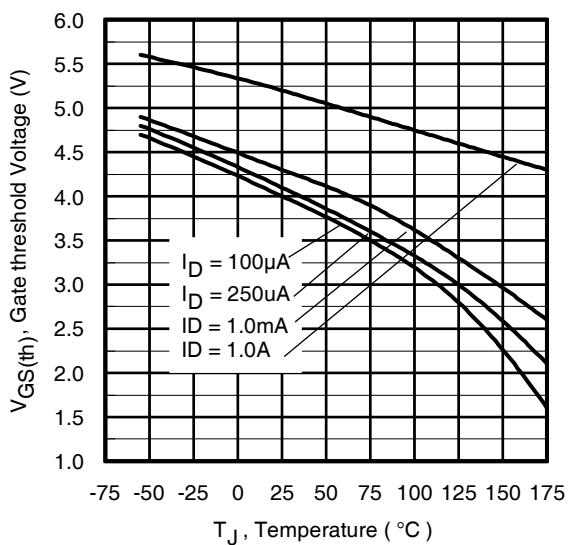
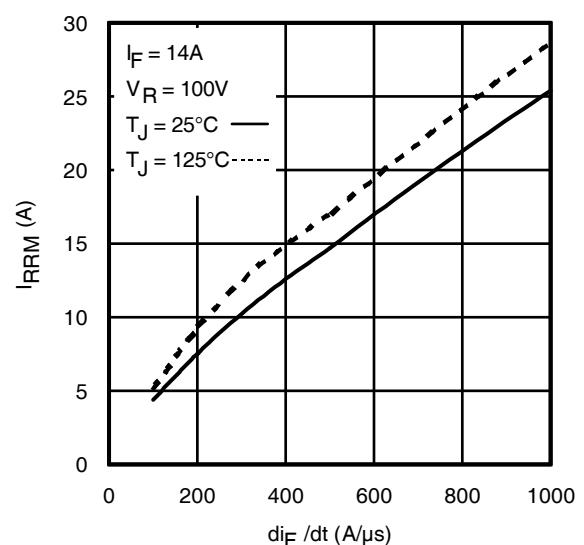
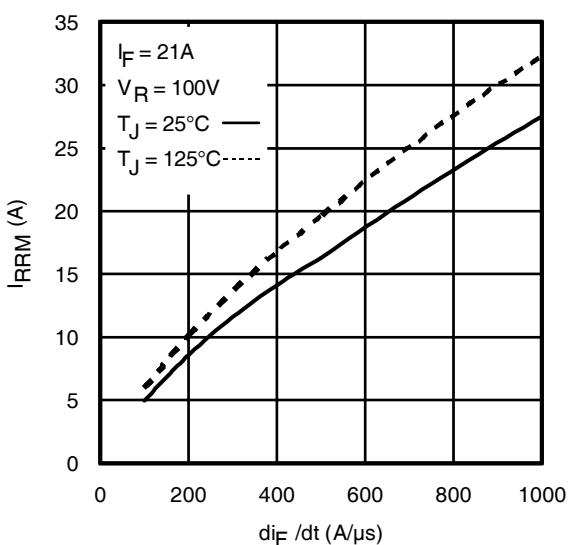
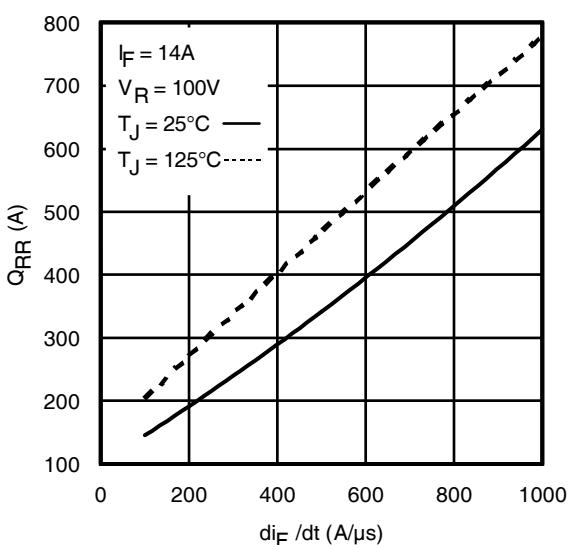
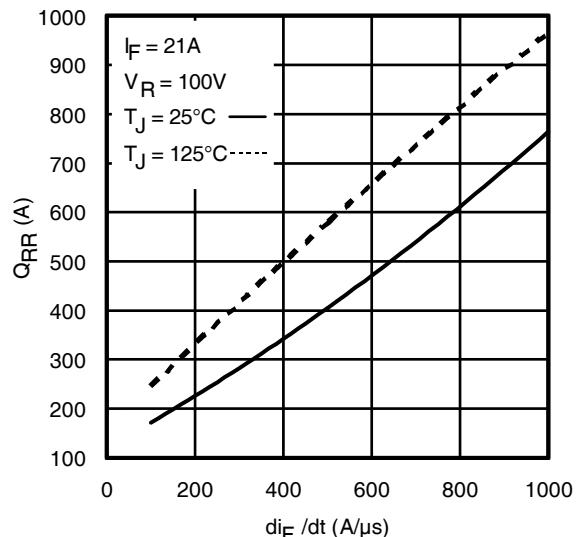
1. Avalanche failures assumption:  
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
4.  $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6.  $I_{av}$  = Allowable avalanche current.
7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as  $25^{\circ}\text{C}$  in Figure 14, 15).
- $t_{av}$  = Average time in avalanche.
- $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$
- $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

Fig 15. Maximum Avalanche Energy vs. Temperature

**Fig. 16.** Threshold Voltage vs. Temperature**Fig. 17 -** Typical Recovery Current vs.  $di_F/dt$ **Fig. 18 -** Typical Recovery Current vs.  $di_F/dt$ **Fig. 19 -** Typical Stored Charge vs.  $di_F/dt$ **Fig. 20 -** Typical Stored Charge vs.  $di_F/dt$

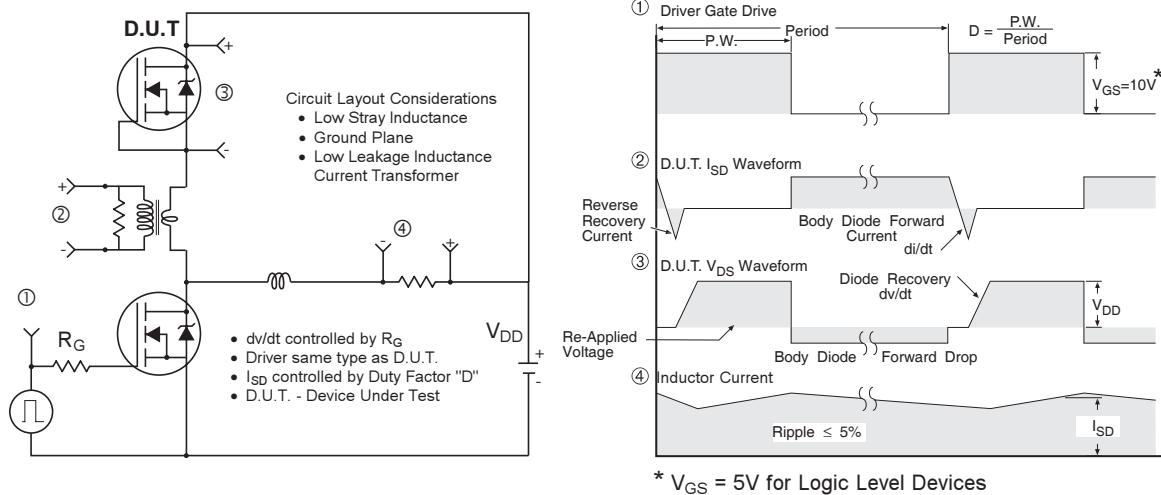


Fig 21. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs

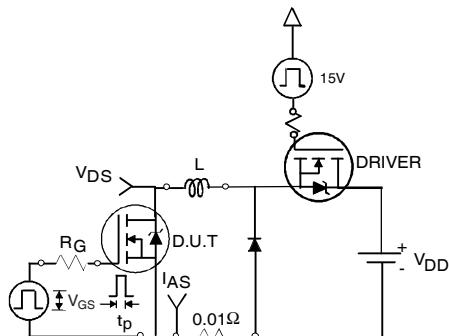


Fig 22a. Unclamped Inductive Test Circuit

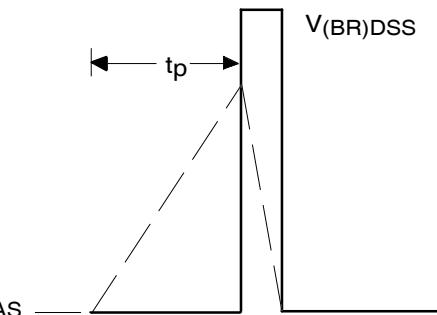


Fig 22b. Unclamped Inductive Waveforms

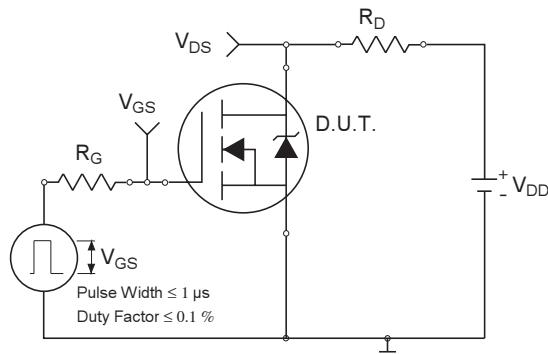


Fig 23a. Switching Time Test Circuit

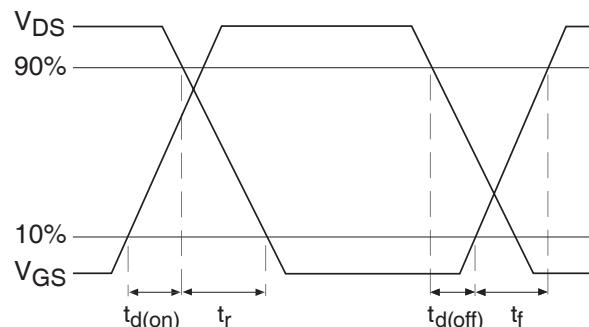


Fig 23b. Switching Time Waveforms

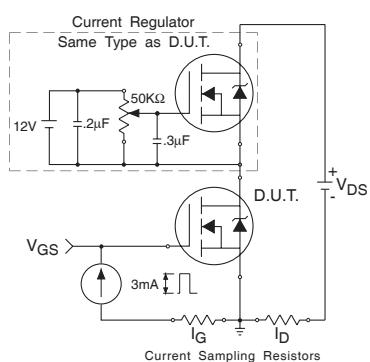


Fig 24a. Gate Charge Test Circuit

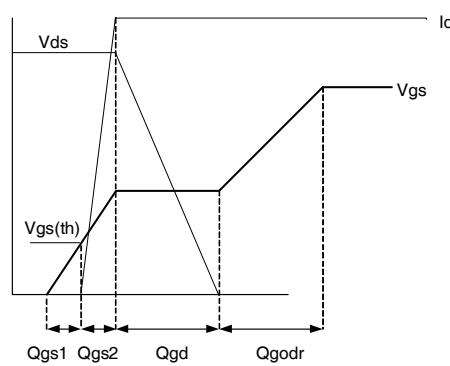
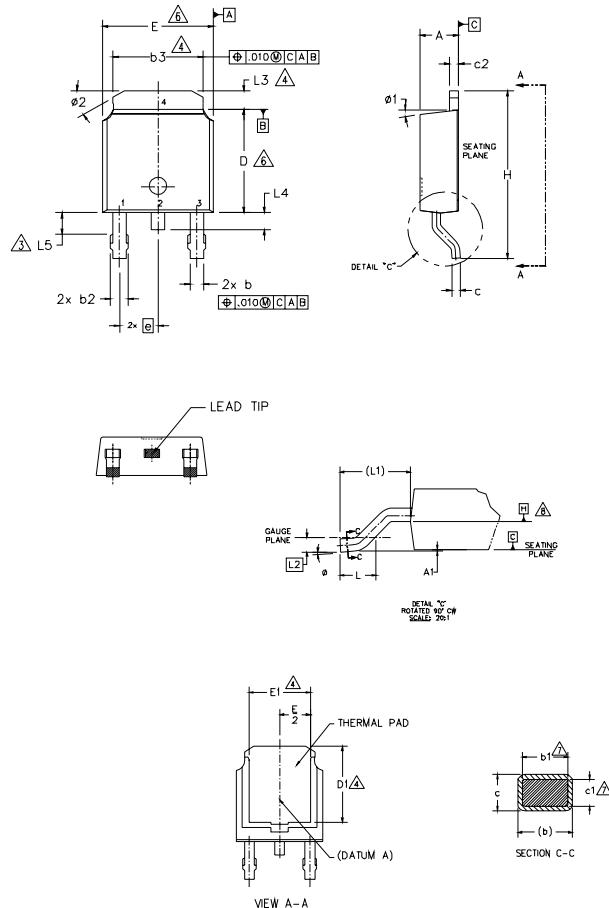


Fig 24b. Gate Charge Waveform

## D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



## NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- LEAD DIMENSION UNCONTROLLED IN L5.
- 4.- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 6.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 7.- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- 8.- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

SYMBOL	DIMENSIONS		NOTES
	MILLIMETERS	INCHES	
	MIN.	MAX.	
A	2.18	.239	.086 .094
A1	—	.013	— .005
b	0.64	.089	.025 .035
b1	0.65	.079	.025 .031
b2	0.76	.114	.030 .045
b3	4.95	.546	.195 .215
c	0.46	.061	.018 .024
c1	0.41	.056	.016 .022
c2	0.46	.089	.018 .035
D	5.97	.622	.235 .245
D1	5.21	—	.205 —
E	6.35	.673	.250 .265
E1	4.32	—	.170 —
e	2.29 BSC	.090 BSC	
H	9.40	.1041	.370 .410
L	1.40	.178	.055 .070
L1	2.74 BSC	.108 REF.	
L2	0.51 BSC	.020 BSC	
L3	0.89	.127	.035 .050
L4	—	1.02	— .040
L5	1.14	.152	.045 .060
Ø	0°	10°	0° 10°
Ø1	0°	15°	0° 15°
Ø2	25°	35°	25° 35°

LEAD ASSIGNMENTSHEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

IGBT & CoPAK

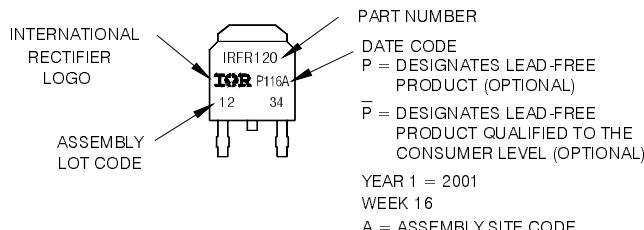
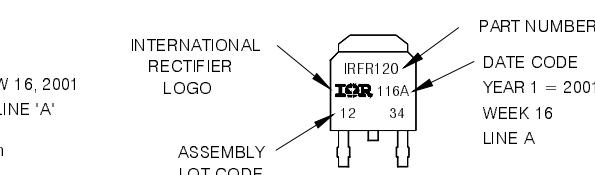
- 1.- GATE
- 2.- COLLECTOR
- 3.- Emitter
- 4.- COLLECTOR

## D-Pak (TO-252AA) Part Marking Information

EXAMPLE: THIS IS AN IRFR120  
WITH ASSEMBLY  
LOT CODE 1234  
ASSEMBLED ON WW 16, 2001  
IN THE ASSEMBLY LINE 'A'

Note: 'P' in assembly line position  
indicates 'Lead-Free'

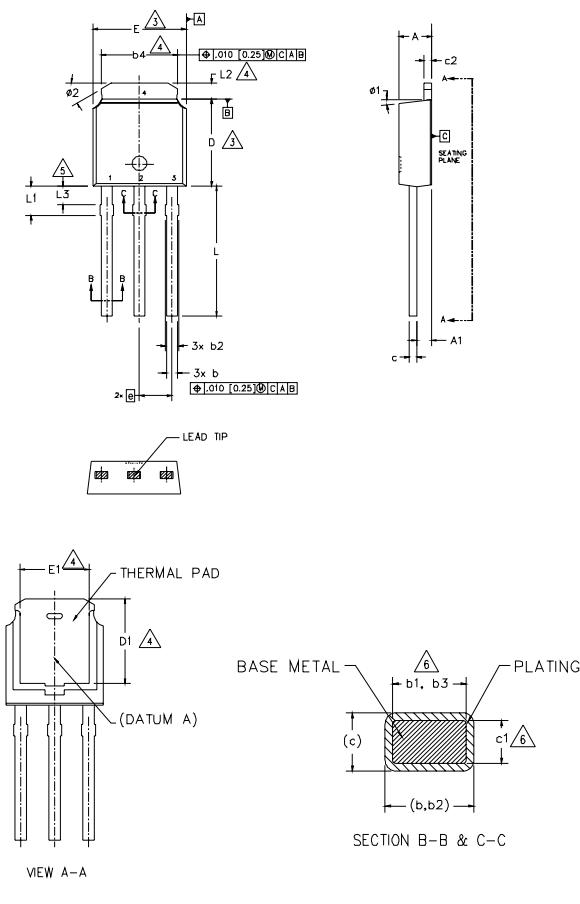
'P' in assembly line position indicates  
'Lead-Free' qualification to the consumer-level

OR

**Note:** For the most current drawing please refer to IR website at <http://www.irf.com/package/>

## I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



### NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3.- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4.- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION b4, L2, E1 & D1.
- 5.- LEAD DIMENSION UNCONTROLLED IN L3.
- 6.- DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

SYMBOL	DIMENSIONS			NOTES
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	.086	.094
A1	0.89	1.14	.035	.045
b	0.64	0.89	.025	.035
b1	0.65	0.79	.025	.031
b2	0.76	1.14	.030	.045
b3	0.76	1.04	.030	.041
b4	4.95	5.46	.195	.215
c	0.46	0.61	.018	.024
c1	0.41	0.56	.016	.022
c2	0.46	0.89	.018	.035
D	5.97	6.22	.235	.245
D1	5.21	—	.205	—
E	6.35	6.73	.250	.265
E1	4.32	—	.170	—
e	2.29	BSC	.090	BSC
L	8.89	9.65	.350	.380
L1	1.91	2.29	.045	.090
L2	0.89	1.27	.035	.050
L3	1.14	1.52	.045	.060
ø1	0°	15°	0°	15°
ø2	25°	35°	25°	35°

### LEAD ASSIGNMENTS

#### HEXFET

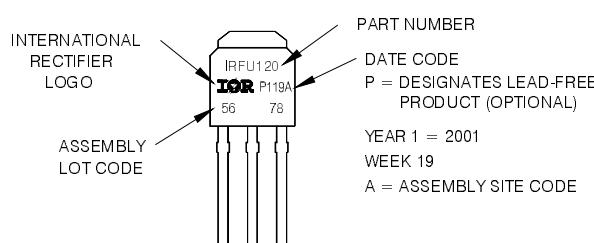
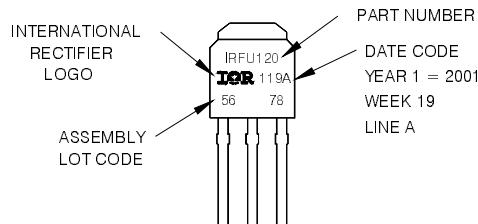
- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

## I-Pak (TO-251AA) Part Marking Information

EXAMPLE: THIS IS AN IRFU120  
WITH ASSEMBLY  
LOT CODE 5678  
ASSEMBLED ON WW 19, 2001  
IN THE ASSEMBLY LINE 'A'

Note: 'P' in assembly line position  
indicates Lead-Free'

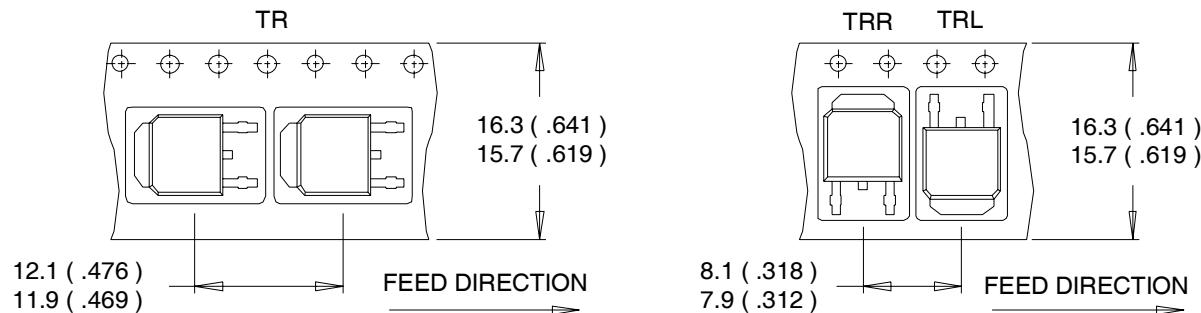
OR



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

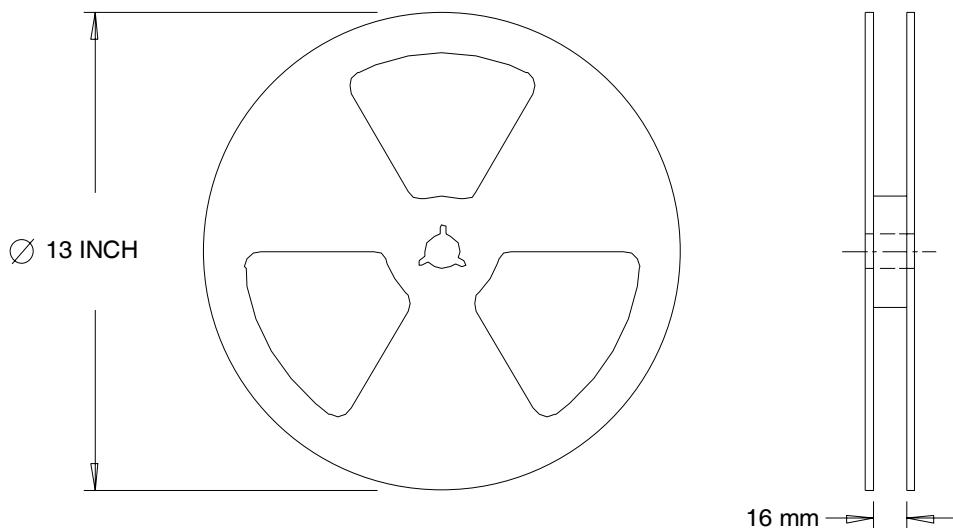
## D-Pak (TO-252AA) Tape &amp; Reel Information

Dimensions are shown in millimeters (inches)



## NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



## NOTES :

1. OUTLINE CONFORMS TO EIA-481.

Orderable part number	Package Type	Standard Pack		Note
		Form	Quantity	
IRFR4615PbF	D-PAK	Tube/Bulk	75	
IRFR4615TRPbF	D-PAK	Tape and Reel	2000	
IRFU4615PbF	I-PAK	Tube/Bulk	75	

### Qualification Information<sup>†</sup>

Qualification level	Industrial <sup>++</sup>	
	(per JEDEC JESD47F <sup>+++</sup> guidelines)	
	Comments: This family of products has passed JEDEC's Industrial qualification. IR's Consumer qualification level is granted by extension of the higher Industrial level.	
Moisture Sensitivity Level	D-PAK	MSL1
	I-PAK	(per JEDEC J-STD-020D <sup>+++</sup> ) Not applicable
RoHS Compliant	Yes	

<sup>†</sup> Qualification standards can be found at International Rectifier's web site <http://www.irf.com/product-info/reliability>

<sup>++</sup> Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: <http://www.irf.com/whoto-call/salesrep/>  
<sup>+++</sup> Applicable version of JEDEC standard at the time of product release.

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^\circ C$ ,  $L = 0.51mH$   
 $R_G = 25\Omega$ ,  $I_{AS} = 21A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value .
- ③  $I_{SD} \leq 21A$ ,  $dI/dt \leq 549A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 175^\circ C$ .
- ④ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .

- ⑤  $C_{oss}$  eff. (TR) is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑥  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ C$

Data and specifications subject to change without notice

International  
**IR** Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
TAC Fax: (310) 252-7903

Visit us at [www.irf.com](http://www.irf.com) for sales contact information. 06/2009